Differential Input, Dual, Simultaneous Sampling, 3 MSPS, 12-Bit, SAR ADC

Preliminary Technical Data

AD7352

FEATURES

Dual 12-bit SAR ADC
Simultaneous Sampling
Throughput rate: 3 MSPS Per Channel
Specified for V$_{DD}$ of 2.5 V
No latency to 12 bits
Power dissipation:
   23 mW at 3 MSPS
On-chip reference:
   2.048 V ± 0.5% max @ 25°C, 10ppm/°C
Dual conversion with read
High speed serial interface:
   SPI®-/QSPI™-/MICROWIRE™-/DSP-compatible
−40°C to +125°C operation
Shutdown mode: 10 µA max
16-lead TSSOP package

FUNCTIONAL BLOCK DIAGRAM

Figure 1.

GENERAL DESCRIPTION

The AD7352[1] is a dual, 12-bit and 14-bit, high speed, low power, successive approximation ADC that operates from a single 2.5 V power supply and features throughput rates up to 3 MSPS. The part contains two ADCs, each preceded by a low noise, wide bandwidth track-and-hold circuit that can handle input frequencies in excess of 200 MHz.

The conversion process and data acquisition use standard control inputs allowing for easy interfacing to microprocessors or DSPs. The input signal is sampled on the falling edge of $\overline{CS}$; conversion is also initiated at this point. The conversion time is determined by the SCLK frequency.

The AD7352 uses advanced design techniques to achieve very low power dissipation at high throughput rates. With 2.5 V supply and a 3 MSPS throughput rate, the part consumes 9.2mA typically. The part also offers flexible power/throughput rate management when operating in normal mode as the quiescent current consumption is so low.

The analog input range for the parts is the differential common mode +/- Vref/2. The AD7352 has an on-chip 2.048 V reference that can be overdriven when an external reference is preferred.

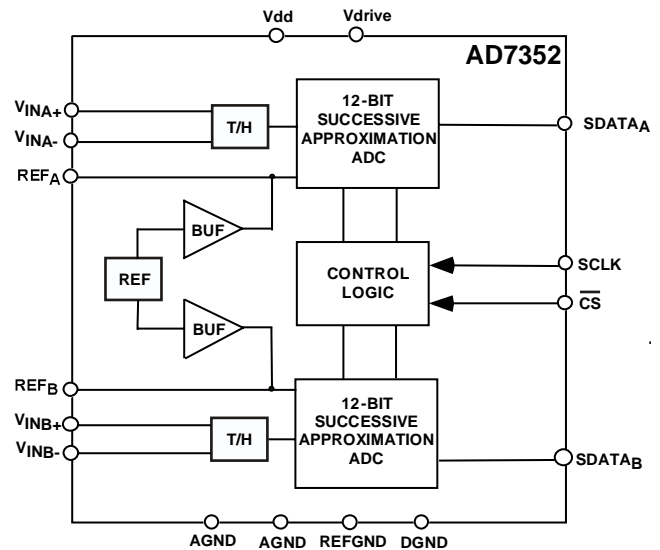The AD7352 is available in a 16-lead thin shrink small outline package (TSSOP).

PRODUCT HIGHLIGHTS

1. Two Complete ADC Functions Allow Simultaneous Sampling and Conversion of Two Channels.
   The conversion result of both channels is simultaneously available on separate data lines or in succession on one data line if only one serial port is available.

2. High Throughput with Low Power Consumption.
   The AD7352 offers a 3 MSPS throughput rate with 23 mW power consumption.

3. The part features two standard successive approximation ADCs with accurate control of the sampling instant via a $\overline{CS}$ input and once off conversion control.

[1] Protected by U.S. Patent No. 6,681,332

Table 1: Related Devices.

Generic	Resolution	Throughput	Analog Input
AD7356	12	5MSPS	Differential
AD7357	14	4.25MSPS	Differential

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REVISION HISTORY

09/07—Revision PrC

SPECIFICATIONS

AD7352 SPECIFICATIONS

V_{DD} = 2.5 V ±10%, V_{DRIVE} = 2.5 V to 3.3 V, internal V_{REF} = 2.048 V, unless otherwise noted, F_{CLKIN} = 48 MHz, F_{SAMPLE} = 3 MSPS; T_A = T_{MIN} to T_{MAX}[1], unless otherwise noted.

Table 1.

Parameter	Specification	Unit	Test Conditions/Comments
DYNAMIC PERFORMANCE			f_{IN} = 1.5 MHz sine wave
Signal-to-Noise Ratio (SNR)	70	dB min	
Signal-to-Noise and Distortion (SINAD)	69	dB min	
Total Harmonic Distortion (THD)	−74	dB max	
Spurious Free Dynamic Range (SFDR)	TBD	dB max	
Intermodulation Distortion (IMD)			fa = TBD Hz, fb = TBD Hz
Second Order Terms	TBD	dB typ	
Third Order Terms	TBD	dB typ	
Channel-to-Channel Isolation	−85	dB typ	f_{IN} = TBD kHz, f_{NOISE} = TBD kHz
SAMPLE AND HOLD			
Aperture Delay	5	ns max	
Aperture Delay Matching	40	ps max	
Aperture Jitter	15	ps typ	
Full Power Bandwidth	200	MHz typ	@ 3 dB
	30	MHz typ	@ 0.1 dB
DC ACCURACY			
Resolution	12	Bits	
Integral Nonlinearity	±1	LSB max	
Differential Nonlinearity	±0.99	LSB max	Guaranteed no missed codes to 12 bits
Offset Error	±3	LSB max	
Offset Error Match	±1	LSB typ	
	±6	LSB max	
Gain Error	±3	LSB max	
Gain Error Match	±1	LSB typ	
	±6	LSB max	
ANALOG INPUT			
Fully Differential Input Range: V_{in+} and V_{in-}	$V_{CM} \pm V_{REF}/2$	V	V_{CM} = common-mode voltage , V_{in+} and V_{in-} must remain within GND/V_{DD}
DC Leakage Current	±1	µA max	
Input Capacitance	35	pF typ	When in track
	10	pF typ	When in hold
REFERENCE INPUT/OUTPUT			
V_{REF} Input Voltage Range	2.048+100mV / Vdd	V min / V max	
DC Leakage Current	±1	µA max	
V_{REF} Output Voltage	2.048	V	±0.5% max @ 25°C
V_{REF} Temperature Coefficient	10	ppm/°C max	
V_{REF} Long Term Stability	100	ppm typ	For 1000 hours
V_{REF} Output Voltage Hysteresis[2]	50	ppm typ	
V_{REF} Noise	TBD	µV Typ	
V_{REF} Output Impedance	TBD	Ω Typ	
V_{REF} Input Capacitance	TBD	pF typ	When in track
LOGIC INPUTS			
Input High Voltage, V_{INH}	0.6 × Vdrive	V min	
Input Low Voltage, V_{INL}	0.3 × Vdrive	V max	
Input Current, I_{IN}	±1	µA max	V_{IN} = 0 V or V_{DRIVE}
Input Capacitance, C_{IN}	10	pF typ	

Parameter	Specification	Unit	Test Conditions/Comments
LOGIC OUTPUTS			
Output High Voltage, V_{OH}	Vdrive-0.2	V min	
Output Low Voltage, V_{OL}	0.2	V max	
Floating-State Leakage Current	±1	µA max	
Floating-State Output Capacitance	TBD	pF typ	
Output Coding	Straight Binary		
CONVERSION RATE			
Conversion Time	$t_2 + 13 \times t_{SCLK}$	ns	
Track-and-Hold Acquisition Time	30	ns max	Full-scale step input
Throughput Rate	3	MSPS max	
POWER REQUIREMENTS			
V_{DD}	2.5 ±10%	V	
V_{DRIVE}	2.5/3.3	V min/max	
I_{TOTAL}[3]			Digital I/P$_S$ = 0 V or V_{DRIVE}
Normal Mode (Operational)	10	mA max	
Normal Mode (Static)	7	mA max	SCLK on or off
Partial Power-Down Mode	8	mA max	
Full Power-Down Mode	10	µA max	SCLK on or off
Power Dissipation			
Normal Mode (Operational)	25	mW max	
Normal Mode (Static)	17.5	mW max	SCLK on or off
Partial Power-Down Mode	12.5	mW max	
Full Power-Down Mode	2.5	µW max	SCLK on or off

[1] Temperature ranges are as follows: Y Grade: −40°C to +125°C , B Grade: −40°C to +85°C.
[2] See the Terminology section.
[3] I_{TOTAL} is the total current flowing in V_{DD} and V_{DRIVE}

TIMING SPECIFICATIONS

V_{DD} = 2.5 V ±10%, V_{DRIVE} = 2.5 V to 3.3 V, internal reference = 2.048 V, T_A = T_{MAX} to T_{MIN}[1], unless otherwise noted.

Table 2.

Parameter	Limit at T_{MIN}, T_{MAX}	Unit	Description
f_{SCLK}	50	kHz min	
	48	MHz max	
$t_{CONVERT}$	t_2 +13 × t_{SCLK}	ns max	t_{SCLK} = 1/f_{SCLK}
t_{QUIET}	5	ns min	Minimum time between end of serial read and next falling edge of $\overline{CS}$
t_2	5	ns min	$\overline{CS}$ to SCLK setup time
t_3	TBD	ns max	Delay from $\overline{CS}$ until $D_{OUT}A$ and $D_{OUT}B$ are three-state disabled
t_4[2]	TBD	ns max	Data access time after SCLK falling edge
t_5	0.40 t_{SCLK}	ns min	SCLK low pulse width
t_6	0.40 t_{SCLK}	ns min	SCLK high pulse width
t_7	TBD	ns min	SCLK to data valid hold time
t_8	TBD	ns max	$\overline{CS}$ rising edge to $D_{OUT}A$, $D_{OUT}B$, high impedance
t_9	TBD	ns min	$\overline{CS}$ rising edge to falling edge pulse width
t_{10}	TBD	ns min	SCLK falling edge to $D_{OUT}A$, $D_{OUT}B$, high impedance
	TBD	ns max	SCLK falling edge to $D_{OUT}A$, $D_{OUT}B$, high impedance

[1] Temperature ranges are as follows: Y Grade: −40℃ to +125℃, B Grade: −40℃ to +85℃.
[2] The time required for the output to cross 0.4 V or 2.4 V.

ABSOLUTE MAXIMUM RATINGS

Table 3.

Parameter	Rating
V_{DD} to AGND, DGND, REFGND	−0.3 V to +2.8 V
V_{DRIVE} to AGND, DGND, REFGND	−0.3 V to +3.8V
V_{DD} to V_{DRIVE}	+2.8V to −3.8V
AGND to DGND to REFGND	−0.3 V to +0.3 V
Analog Input Voltages[1] to AGND	−0.3 V to V_{DD} + 0.3 V
Digital Input Voltages[2] to DGND	−0.3V to V_{DRIVE} + 0.3V
Digital Output Voltages[3] to DGND	−0.3 V to V_{DRIVE} + 0.3 V
Input Current to Any Pin Except Supplies[4]	±10 mA
Operating Temperature Range	
Y Grade	−40°C to +125°C
B Grade	−40°C to +85°C
Storage Temperature Range	−65°C to +150°C
Junction Temperature	150°C
TSSOP Package	
θ_{JA} Thermal Impedance	143°C/W
θ_{JC} Thermal Impedance	45°C/W
Lead Temperature, Soldering	
Reflow Temperature (10 to 30 sec)	255°C
ESD	TBD kV

[1] Analog input voltages are V_{INA+}, V_{INA-}, V_{INB+}, V_{INB-}, REF_A and REF_B.
[2] Digital input voltages are $\overline{CS}$ and SCLK.
[3] Digital output voltages are $SDATA_A$ and $SDATA_B$.
[4] Transient currents of up to 100 mA will not cause SCR latch up.

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.
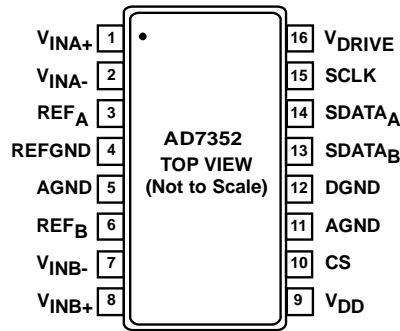

WARNING!
ESD SENSITIVE DEVICE

PIN CONFIGURATION AND FUNCTION DESCRIPTIONS

Figure 2. Pin Configuration

Table 4. Pin Function Descriptions

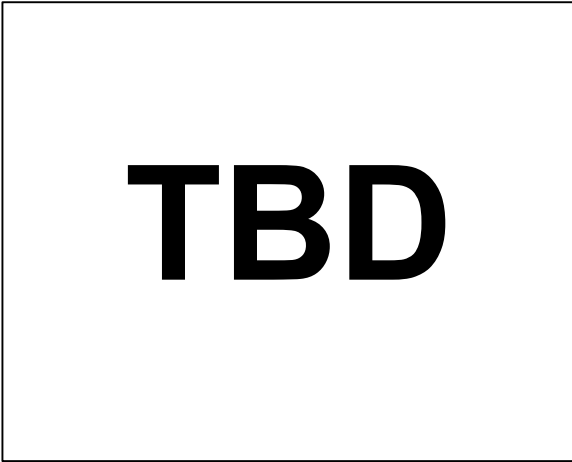| Pin No.	Mnemonic	Description
9	V_{DD}	Power Supply Input. The V_{DD} range for the AD7352 is 2.5V +/- 5%. The supply should be decoupled to AGND with a 0.1 µF capacitor and a 10 µF tantalum capacitor.
16	V_{DRIVE}	Logic Power Supply Input. The voltage supplied at this pin determines at what voltage the interface will operate. This pin should be decoupled to DGND. The voltage at this pin may be different to that at V_{DD}.
10	$\overline{CS}$	Chip Select. Active low logic input. This input provides the dual function of initiating conversions on the AD7352 and framing the serial data transfer.
15	SCLK	Serial Clock. Logic input. A serial clock input provides the SCLK for accessing the data from the AD7352. This clock is also used as the clock source for the conversion process.
14,13	$SDATA_A$, $SDATA_B$	Serial Data Outputs. The data output is supplied to each pin as a serial data stream. The bits are clocked out on the falling edge of the SCLK input. 14 SCLK falling edges are required to access the 12 bits of data from the AD7352. The data simultaneously appears on both data output pins from the simultaneous conversions of both ADCs. The data stream consists of two leading zeros followed by the 12 bits of conversion data. The data is provided MSB first. If CS is held low for 16 SCLK cycles rather than 14 on the AD7352, then two trailing zeros will appear after the 12 bits of data. If CS is held low for a further 16 SCLK cycles on either $SDATA_A$ or $SDATA_B$, the data from the other ADC follows on the SDATA pin. This allows data from a simultaneous conversion on both ADCs to be gathered in serial format on either $SDATA_A$ or $SDATA_B$.
12	DGND	Digital Ground. This is the ground reference point for all digital circuitry on the AD7352. This pin should connect to the DGND plane of a system. The DGND and AGND voltages should ideally be at the same potential and must not be more than 0.3 V apart, even on a transient basis.
5, 11	AGND	Analog Ground. This is the ground reference point for all analog circuitry on the AD7352. All analog input signals should be referred to this AGND voltage. The AGND and DGND voltages should ideally be at the same potential and must not be more than 0.3 V apart, even on a transient basis.
4	REFGND	Reference Ground. This is the ground reference point for the reference circuitry on the AD7352. Any external reference signal should be referred to this REFGND voltage. Decoupling capacitors must be placed between this pin and the REF_A and REF_B pins.
3, 6	REF_A, REF_B	Reference decoupling capacitor pins. Decoupling capacitors are connected between these pins and the REFGND pin to decouple the reference buffer for each respective ADC. It is recommended to decouple each reference pin with a 10µF capacitor. Provided the output is buffered, the on-chip reference can be taken from these pins and applied externally to the rest of the system. The nominal internal reference voltage is 2.048V and this appears at these pins. These pins can also be overdriven by an external reference. The input voltage range for the external reference is 2.048+100mV to Vdd.
1, 2	V_{INA-}, V_{INA+}	Analog Inputs of ADC A. These analog inputs form a fully differential pair.
8, 7	V_{INB-}, V_{INB+}	Analog Inputs of ADC B. These analog inputs form a fully differential pair.

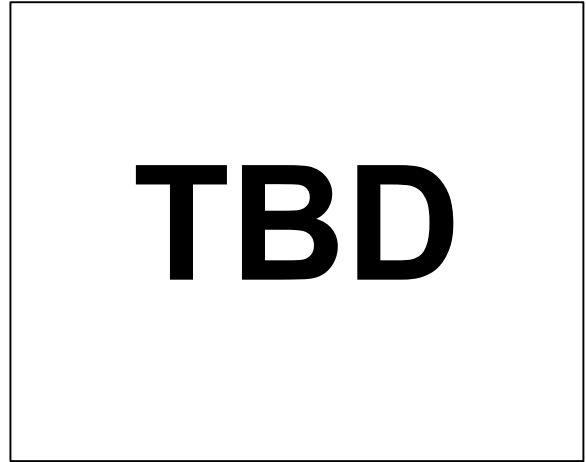## TYPICAL PERFORMANCE CHARACTERISTICS

TBD

Figure 3. Typical FFT

TBD

Figure 6. Channel to Channel Isolation
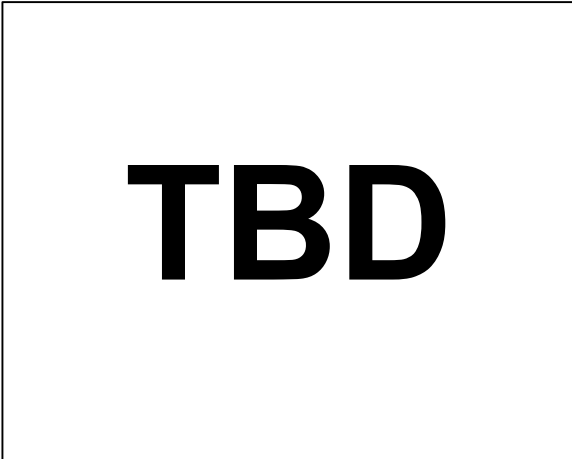
TBD

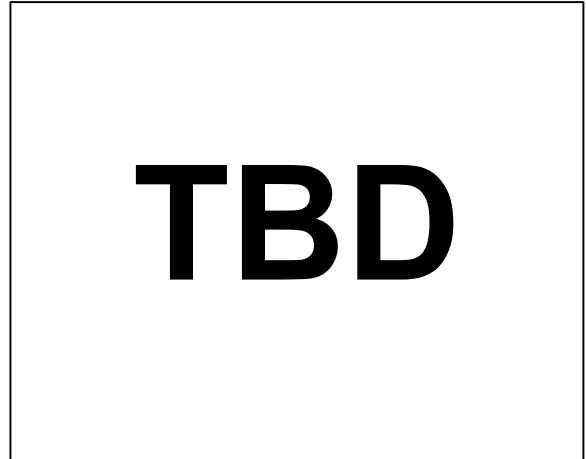*Figure 4. Typical DNL*

TBD

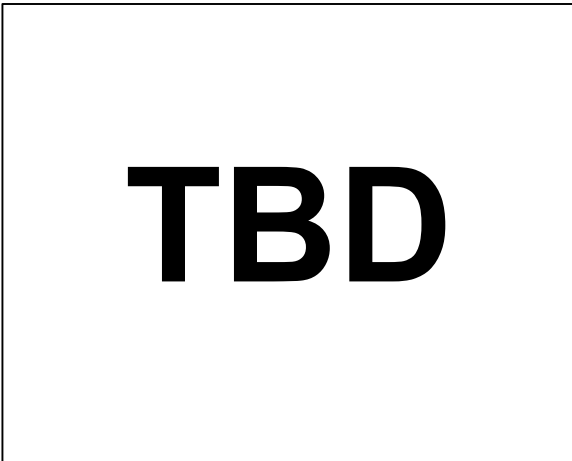*Figure 7. Histogram of Codes*

TBD

Figure 5. Typical INL

TERMINOLOGY

Integral Nonlinearity (INL)
The maximum deviation from a straight line passing through the endpoints of the ADC transfer function. The endpoints of the transfer function are zero scale, 1 LSB below the first code transition, and full scale, 1 LSB above the last code transition.

Differential Nonlinearity (DNL)
The difference between the measured and the ideal 1 LSB change between any two adjacent codes in the ADC.

Offset Error
The deviation of the first code transition (00 . . .000) to (00 . . . 001) from the ideal (that is, -V_{REF} + 0.5 LSB).

Offset Error Match
This is the difference in offset error between the two ADCs.

Gain Error
The deviation of the last code transition (111 . . .110) to (111 . . . 111) from the ideal (that is, V_{REF} – 1.5 LSB) after the offset error has been adjusted out.

Gain Error Match
The difference in gain error between the two ADCs.

Channel-to-Channel Isolation
Channel-to-channel isolation is a measure of the level of crosstalk between channels. It is measured by applying a full-scale sine wave signal to one of the two channels and applying a 50 kHz signal to the other channel. The channel-to-channel isolation is defined as the ratio of the power of the 50 kHz signal on the converted channel to the power of the noise signal on the other channel that appears in the FFT of this channel. The noise frequency on the unselected channel varies from 40 kHz to 740 kHz. The noise amplitude is at $2 \times V_{REF}$, while the signal amplitude is at $1 \times V_{REF}$..

Power Supply Rejection Ratio (PSRR)
PSRR is defined as the ratio of the power in the ADC output at full-scale frequency, *f*, to the power of a 100 mV p-p sine wave applied to the ADC V_{DD} supply of frequency f_S. The frequency of the input varies from 1 kHz to 1 MHz.

$$PSRR \text{ (dB)} = 10\log(Pf/Pf_S)$$

where:

Pf is the power at frequency *f* in the ADC output.
Pf_S is the power at frequency f_S in the ADC output.

Common-Mode Rejection Ratio (CMRR)
CMRR is defined as the ratio of the power in the ADC output at full-scale frequency, *f*, to the power of a 100 mV p-p sine wave applied to the common-mode voltage of V_{IN+} and V_{IN-} of frequency f_S as

$$CMRR \text{ (dB)} = 10\log (Pf/Pf_S)$$

where:

Pf is the power at frequency *f* in the ADC output.
Pf_S is the power at frequency f_S in the ADC output.

Track-and-Hold Acquisition Time
The track-and-hold amplifier returns to track mode at the end of conversion. The track-and-hold acquisition time is the time required for the output of the track-and-hold amplifier to reach its final value, within ±1/2 LSB, after the end of conversion.

Signal-to-(Noise + Distortion) Ratio (SINAD)
This is the measured ratio of signal-to-noise and distortion at the output of the ADC. The signal is the rms amplitude of the fundamental. Noise is the sum of all nonfundamental signals up to half the sampling frequency ($f_S/2$), excluding dc. The ratio is dependent on the number of quantization levels in the digitization process; the more levels, the smaller the quantization noise.

The theoretical signal-to-noise and distortion ratio for an ideal N-bit converter with a sine wave input is given by

$$SINAD = (6.02\ N + 1.76) \text{ dB}$$

Thus, for a 12-bit converter, this is 74 dB and for a 14 bit converter, this is 86dB.

Total Harmonic Distortion (THD)
THD is the ratio of the rms sum of harmonics to the fundamental. For the AD7352, it is defined as

$$THD \text{ (dB)} = -20\log \frac{\sqrt{V_2{}^2 + V_3{}^2 + V_4{}^2 + V_5{}^2 + V_6{}^2}}{V_1}$$

where:

V_1 is the rms amplitude of the fundamental.
V_2, V_3, V_4, V_5, and V_6 are the rms amplitudes of the second through the sixth harmonics.

Peak Harmonic or Spurious Noise

Peak harmonic or spurious noise is defined as the ratio of the rms value of the next largest component in the ADC output spectrum (up to $f_S/2$ and excluding dc) to the rms value of the fundamental. Normally, the value of this specification is determined by the largest harmonic in the spectrum, but for ADCs where the harmonics are buried in the noise floor, it is a noise peak

Intermodulation Distortion

With inputs consisting of sine waves at two frequencies, *fa* and *fb*, any active device with nonlinearities will create distortion products at sum and difference frequencies of mfa ± nfb where m, n = 0, 1, 2, 3, and so on. Intermodulation distortion terms are those for which neither *m* nor *n* are equal to zero. For example, the second-order terms include (*fa* + *fb*) and (*fa* − *fb*), while the third-order terms include (*2fa* + *fb*), (*2fa* − *fb*), (*fa* + *2fb*), and (*fa* − *2fb*).

The AD7352 is tested using the CCIF standard where two input frequencies near the top end of the input bandwidth are used. In this case, the second-order terms are usually distanced in frequency from the original sine waves, while the third-order terms are usually at a frequency close to the input frequencies. As a result, the second- and third-order terms are specified separately. The calculation of the intermodulation distortion is as per the THD specification, where it is the ratio of the rms sum of the individual distortion products to the rms amplitude of the sum of the fundamentals expressed in dBs.

Thermal Hysteresis

Thermal Hysteresis is defined as the absolute maximum change of reference output voltage after the device is cycled through temperature from either

$$T\_HYS+ = +25°C \text{ to } T_{MAX} \text{ to } +25°C$$
$$T\_HYS- = +25°C \text{ to } T_{MIN} \text{ to } +25°C$$

It is expressed in ppm using the following equation:

$$V_{HYS}(ppm) = \left| \frac{V_{REF}(25°C) - V_{REF}(T\_HYS)}{V_{REF}(25°C)} \right| \times 10^6$$

where:
$V_{REF}(25°C) = V_{REF}$ at 25°C
$V_{REF}(T_HYS) = $ Maximum change of V_{REF} at T_HYS+ or T_HYS−.

THEORY OF OPERATION

CIRCUIT INFORMATION

The AD7352 is a fast, dual, 12-bit , single-supply, successive approximation analog-to-digital converter. The part operates from a 2.5 V power supply and features throughput rates up to 3MSPS.

The AD7352 contains two on-chip differential track-and-hold amplifiers, two successive approximation analog-to-digital converters and a serial interface with two separate data output pins. They part is housed in a 16-lead TSSOP package, offering the user considerable space-saving advantages over alternative solutions.

The serial clock input accesses data from the part, but also provides the clock source for each successive approximation ADC. The AD7352 has an on-chip 2.048V reference. If an external reference is desired the internal reference can be overdriven with a reference of value ranging from (2.048V + 100mV) to Vdd. If the internal reference is to be used elsewhere in the system, then the reference output needs to be buffered first. The analog input range for the AD7352 is 0 to V_{REF}.

The AD7352 features power-down options to allow power saving between conversions. The power-down feature is implemented via the standard serial interface, as described in the Modes of Operation section.

CONVERTER OPERATION

The AD7352 has two successive approximation analog-to-digital converters, each based around two capacitive DACs. Figure 8 and Figure 9 show simplified schematics of one of these ADCs in acquisition and conversion phase, respectively. The ADC is comprised of control logic, a SAR, and two capacitive DACs. In Figure 8 (the acquisition phase), SW3 is closed, SW1 and SW2 are in position A, the comparator is held in a balanced condition, and the sampling capacitor arrays may acquire the differential signal on the input.
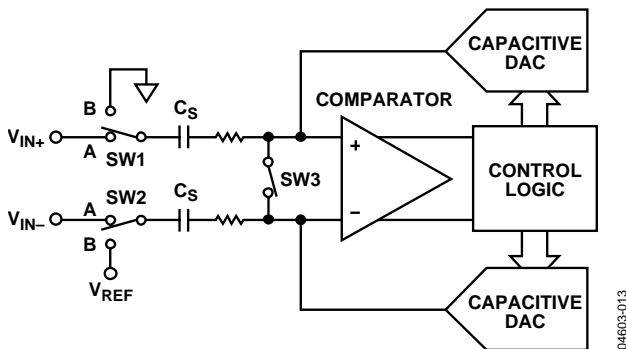

Figure 8. ADC Acquisition Phase

When the ADC starts a conversion (Figure 9), SW3 opens and SW1 and SW2 move to Position B, causing the comparator to become unbalanced. Both inputs are disconnected once the

conversion begins. The control logic and charge redistribution DACs are used to add and subtract fixed amounts of charge from the sampling capacitor arrays to bring the comparator back into a balanced condition. When the comparator is rebalanced, the conversion is complete. The control logic generates the ADC output code. The output impedances of the sources driving the V_{IN+} and V_{IN-} pins must be matched, otherwise, the two inputs will have different settling times, resulting in errors.
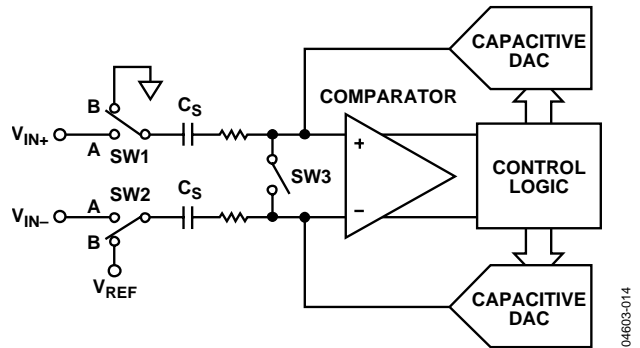

Figure 9. ADC Conversion Phase

ADC TRANSFER FUNCTION

The output coding for the AD7352 is straight binary. The designed code transitions occur at successive LSB values (1 LSB, 2 LSBs and so on). The LSB size is $(2 \times V_{REF})/4096$ for the AD7352. The ideal transfer characteristic of the AD7352 is shown in Figure 10.
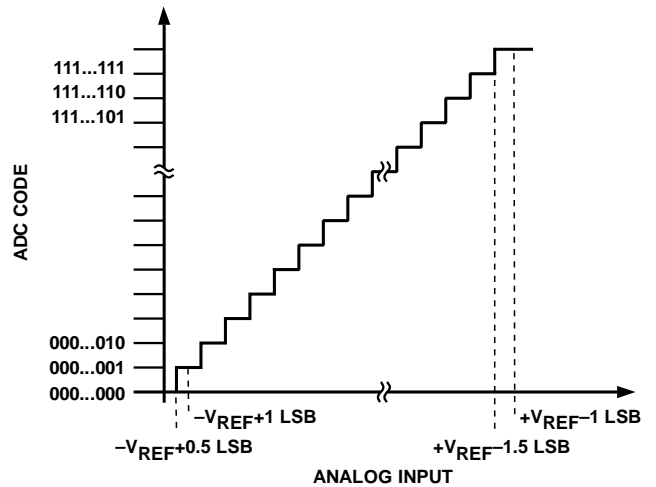

Figure 10. AD7352 Ideal Transfer Characteristic

ANALOG INPUT STRUCTURE

Figure 11 shows the equivalent circuit of the analog input structure of the AD7352. The four diodes provide ESD protection for the analog inputs. Care must be taken to ensure that the analog input signals never exceed the supply rails by more than 300mV. This causes these diodes to become forward-biased and start conducting into the substrate. These diodes can

conduct up to 10mA without causing irreversible damage to the part.

The C1 capacitors in Figure 11 are typically TBD pF and can primarily be attributed to pin capacitance. The resistors are lumped components made up of the on resistance of the switches. The value of these resistors is typically about TBD Ω. The C2 capacitors are the ADC's sampling capacitors with a capacitance of TBD pF typically.
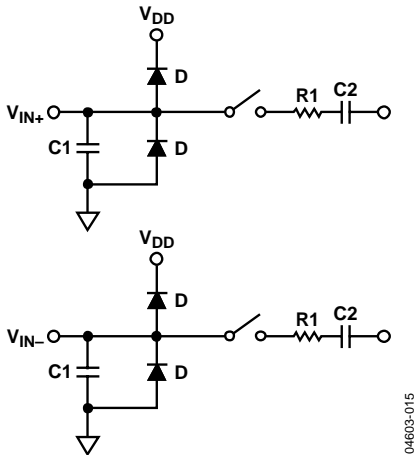

Figure 11.Equivalent Analog Input Circuit,
Conversion Phase – Switches Open, Track Phase – Switches Closed

For ac applications, removing high frequency components from the analog input signal is recommended by the use of an RC low-pass filter on the analog input pins. In applications where harmonic distortion and signal-to-noise ratio are critical, the analog input should be driven from a low impedance source. Large source impedances significantly affect the ac performance of the ADC and may necessitate the use of an input buffer amplifier. The choice of the op amp will be a function of the particular application.
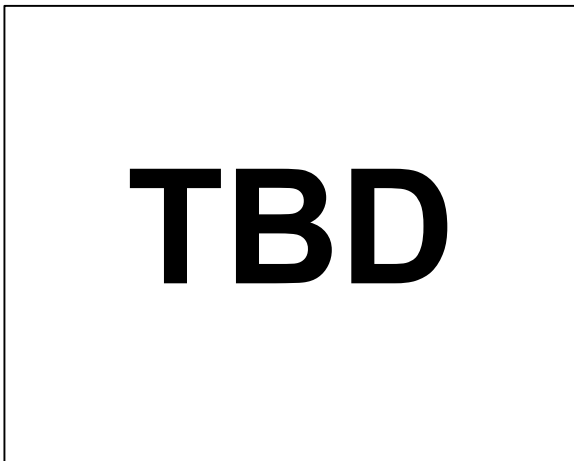

Figure 12.THD vs. Analog Input Frequency for Various Source Impedances

When no amplifier is used to drive the analog input, the source impedance should be limited to low values. The maximum source impedance will depend on the amount of THD that can be tolerated. The THD increases as the source impedance increases and performance degrades. Figure 12 shows a graph of the THD vs. the analog input signal frequency for different source impedances.

Figure 13 shows a graph of the THD vs. the analog input frequency while sampling at 3MSPS. In this case the source impedance is TBD Ω.
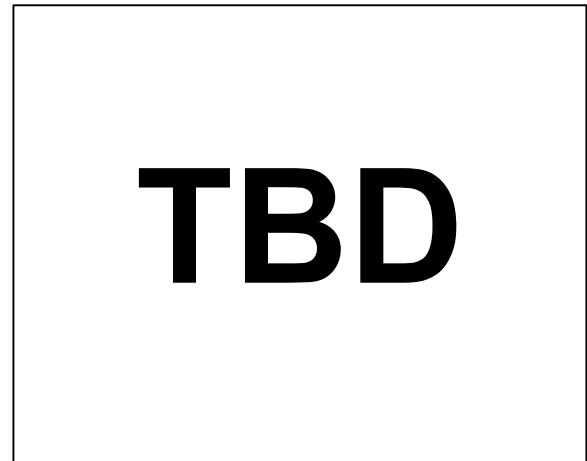

Figure 13.THD vs. Analog Input Frequency

ANALOG INPUTS

Differential signals have some benefits over single-ended signals, including noise immunity based on the devices common-mode rejection and improvements in distortion performance.

The amplitude of the differential signal is the difference between the signals applied to the V_{IN+} and V_{IN-} pins in each differential pair (V_{IN+} - V_{IN-}). V_{IN+} and V_{IN-} should be simultaneously driven by two signals each of amplitude V_{REF} that are 180° out of phase. This amplitude of the differential signal is, therefore $-V_{REF}$ to $+V_{REF}$ peak-to –peak regardless of the common mode (CM).

The common mode is the average of the two signals and is therefore the voltage on which the two inputs are centered.

$$CM = (V_{IN+} + V_{IN-})/2$$

This results in the span of each input being CM ± V_{REF}/2. This voltage has to be set up externally. When a conversion takes place the common mode is rejected resulting in a virtually noise free signal of amplitude $-V_{REF}$ to $+V_{REF}$ corresponding to the digital codes of 0 to 4095 for the AD7352.

MODES OF OPERATION

The mode of operation of the AD7352 is selected by controlling the (logic) state of the $\overline{CS}$ signal during a conversion. There are three possible modes of operation: normal mode, partial power-down mode and full power-down mode. After a conversion has been initiated, the point at which $\overline{CS}$ is pulled high determines which power-down mode, if any, the device enters. Similarly, if already in a power-down mode, $\overline{CS}$ can control whether the device returns to normal operation or remains in power-down. These modes of operation are designed to provide flexible power management options. These options can be chosen to optimize the power dissipation/throughput rate ratio for the differing application requirements.

NORMAL MODE

This mode is intended for applications needing fastest throughput rates since the user does not have to worry about any power-up times with the AD7352 remaining fully powered at all times. Figure 14 shows the general diagram of the operation of the AD7352 in this mode.
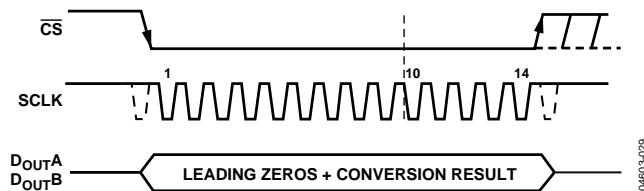

Figure 14. Normal Mode Operation

The conversion is initiated on the falling edge of $\overline{CS}$, as described in the Serial Interface section. To ensure that the part remains fully powered up at all times, $\overline{CS}$ must remain low until at least 10 SCLK falling edges have elapsed after the falling edge of $\overline{CS}$. If $\overline{CS}$ is brought high any time after the 10th SCLK falling edge but before the 14th SCLK falling edge, the part remains powered up, but the conversion is terminated and SDATA$_A$ and SDATA$_B$ go back into three-state. 14 serial clock cycles are required to complete the conversion and access the conversion result for the AD7352. The SDATA lines do not return to three-state after 14 SCLK cycles have elapsed, but instead do so when $\overline{CS}$ is brought high again. If $\overline{CS}$ is left low for another 2 SCLK cycles, two trailing zeros are clocked out after the data. If $\overline{CS}$ is left low for a further 14 SCLK cycles, the result for the other ADC on board is also accessed on the same SDATA line as shown in Figure 20 (see the Serial Interface section).

Once 32 SCLK cycles have elapsed, the SDATA line returns to three-state on the 32nd SCLK falling edge. If $\overline{CS}$ is brought high prior to this, the SDATA line returns to three-state at that point. Thus, $\overline{CS}$ may idle low after 32 SCLK cycles until it is brought high again sometime prior to the next conversion if so desired, since the bus still returns to three-state upon completion of the dual result read.

Once a data transfer is complete and SDATA$_A$ and SDATA$_B$ have returned to three-state, another conversion can be initiated after the quiet time, t_{QUIET}, has elapsed by bringing $\overline{CS}$ low again (assuming the required acquisition time has been allowed).

PARTIAL POWER-DOWN MODE

This mode is intended for use in applications where slower throughput rates are required. Either the ADC is powered down between each conversion, or a series of conversions may be performed at a high throughput rate and the ADC is then powered down for a relatively long duration between these bursts of several conversions. When the AD7352 is in partial power-down, all analog circuitry is powered down except for the on-chip reference and reference buffers.

To enter partial power, the conversion process must be interrupted by bringing $\overline{CS}$ high anywhere after the 2nd falling edge of SCLK and before the 10th falling edge of SCLK, as shown in Figure 15. Once $\overline{CS}$ has been brought high in this window of SCLKs, the part enters partial power-down, the conversion that was initiated by the falling edge of $\overline{CS}$ is terminated, and SDATA$_A$ and SDATA$_B$ go back into three-state. If $\overline{CS}$ is brought high before the 2nd SCLK falling edge, the part remains in normal mode and does not power down. This avoids accidental power-down due to glitches on the $\overline{CS}$ line.
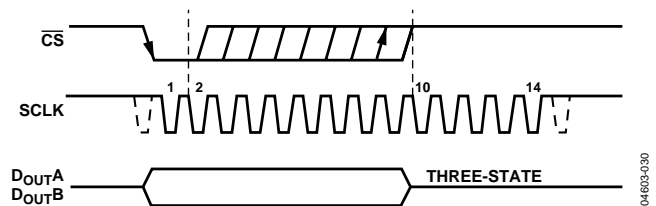

Figure 15. Entering Partial Power-Down Mode

To exit this mode of operation and power up the AD7352 again, a dummy conversion is performed. On the falling of $\overline{CS}$, the device begins to power up, and continues to power up as long as $\overline{CS}$ is held low until after the falling edge of the 10th SCLK. The device is fully powered up after approximately TBD µs has elapsed, and valid data results from the next conversion, as shown in Figure 16. If $\overline{CS}$ is brought high before the 2nd falling edge of SCLK, the AD7352 again goes into partial power-down. This avoids accidental power-up due to glitches on the $\overline{CS}$ line. Although the device may begin to power up on the falling edge of $\overline{CS}$, it powers down again on the rising edge of $\overline{CS}$. If the AD7352 is already in partial power-down mode and $\overline{CS}$ is brought high between the 2nd and 10th falling edges of SCLK, the device enters full power-down mode.

FULL POWER-DOWN MODE

This mode is intended for use in applications where throughput rates slower than those in the partial power-down mode are required, as power-up from a full power-down takes substantially longer than that from a partial power-down. This

mode is more suited to applications where a series of conversions performed at a relatively high throughput rate are followed by a long period of inactivity and thus, power-down. When the AD7352 is in full power-down, all analog circuitry is powered down including the on-chip reference and reference buffers. Full power-down is entered in a similar way as partial power-down, except the timing sequence shown in Figure 15 must be executed twice. The conversion process must be interrupted in a similar fashion by bringing $\overline{CS}$ high anywhere after the 2nd falling edge of SCLK and before the 10th falling edge of SCLK. The device enters partial power down at this point.

To reach full power-down, the next conversion cycle must be interrupted in the same way, as shown in Figure 17. Once $\overline{CS}$

has been brought high in this window of SCLKs, the part completely powers down.

Note that it is not necessary to complete the 14/16 SCLKs once $\overline{CS}$ has been brought high to enter a power-down mode.

To exit full power-down mode and power-up the AD7352, a dummy conversion is performed, as when powering up from partial power-down. On the falling edge of $\overline{CS}$, the device begins to power up, as long as $\overline{CS}$ is held low until after the falling edge of the 10th SCLK. The required power-up time must elapse before a conversion can be initiated, as shown in Figure 18.
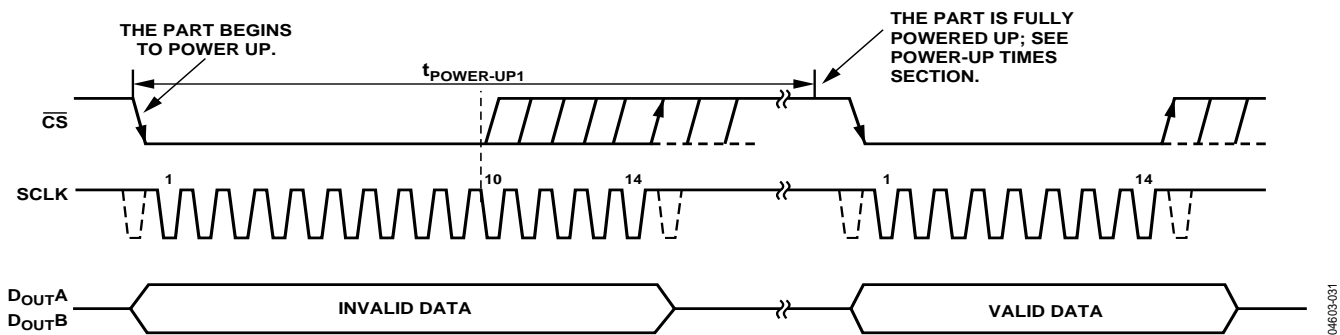

Figure 16. Exiting Partial Power-Down Mode

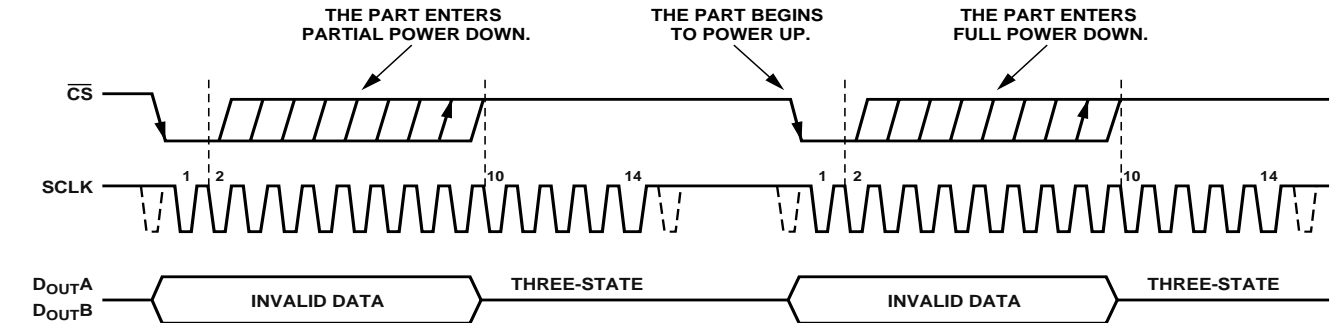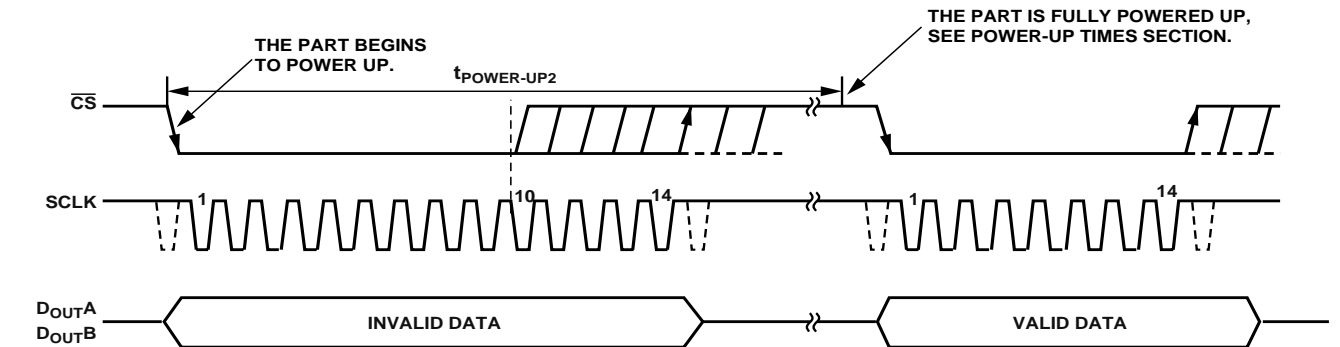Figure 17. Entering Full Power-Down Mode

Figure 18. Exiting Full Power-Down Mode

POWER-UP TIMES

The AD7352 has two power-down modes, partial power-down and full power-down, which are described in detail in the previous sections. This section deals with the power-up time required when coming out of either of these modes.

To power up from partial power-down mode, one dummy cycle is required. The device is fully powered up after approximately TBD μs from the falling edge of $\overline{CS}$ has elapsed. Once the partial power-up time has elapsed, the ADC is fully powered up and the input signal is acquired properly. The quiet time, t_{QUIET}, must still be allowed from the point where the bus goes back into three-state after the dummy conversion to the next falling edge of $\overline{CS}$.

To power up from full power-down, approximately TBD μs should be allowed from the falling edge of $\overline{CS}$, shown in Figure 18 as $t_{POWER-UP2}$.

Note that during power-up from partial power-down mode, the track-and-hold, which is in hold mode while the part is powered down, returns to track mode after the first SCLK edge that the part receives after the falling edge of $\overline{CS}$.

When power supplies are first applied to the AD7352, the ADC can power up in either of the power-down modes or in normal mode. Because of this, it is best to allow a dummy cycle to elapse to ensure that the part is fully powered up before attempting a valid conversion. Likewise, if the part is to be kept in partial power-down mode immediately after the supplies are applied, then two dummy cycles must be initiated. The first dummy cycle must hold $\overline{CS}$ low until after the 10th SCLK falling edge; in the second cycle, $\overline{CS}$ must be brought high between the second and 10th SCLK falling edges (see Figure 15).

Alternatively, if the part is to be placed into full power-down mode when the supplies are applied, three dummy cycles must be initiated. The first dummy cycle must hold $\overline{CS}$ low until after the 10th SCLK falling edge; the second and third dummy cycles place the part into full power-down mode (see Figure 17). See the Modes of Operation section.

SERIAL INTERFACE

Figure 19 shows the detailed timing diagram for serial interfacing to the AD7352. The serial clock provides the conversion clock and controls the transfer of information from the AD7352 during conversion.

The $\overline{CS}$ signal initiates the data transfer and conversion process. The falling edge of $\overline{CS}$ puts the track and hold into hold mode at which point the analog input is sampled and the bus is taken out of three-state. The conversion is also initiated at this point and requires a minimum of 14 SCLKs to complete. Once 13 SCLK falling edges have elapsed, the track and hold will go back into track on the next SCLK rising edge, as shown in Figure 19 at point B. If a 16 bit data transfer is used on the AD7352, then two trailing zeros will appear after the final LSB. On the rising edge of $\overline{CS}$, the conversion will be terminated and SDATA$_A$ and SDATA$_B$ will go back into three-state. If $\overline{CS}$ is not brought high, but is instead held low for a further 14 SCLK cycles on SDATA$_A$, the data from the conversion on ADCB will be output on SDATA$_A$.

Likewise, if $\overline{CS}$ is held low for a further 14 SCLK cycles on SDATA$_A$, the data from the conversion on ADCA will be output on SDATA$_B$. This is illustrated in Figure 20 where the case for SDATA$_A$ is shown. In this case, the SDATA line in use will go

back into three-state on the 32nd SCLK falling edge or the rising edge of $\overline{CS}$, which ever occurs first.

A minimum of 14 serial clock cycles are required to perform the conversion process and to access data from one conversion on either data line of the AD7352. $\overline{CS}$ falling low provides the leading zero to be read in by the microcontroller or DSP. The remaining data is then clocked out by subsequent SCLK falling edges, beginning with a second leading zero. Thus, the first falling clock edge on the serial clock has the leading zero provided and also clocks out the second leading zero. The 12-bit result then follows with the final bit in the data transfer valid on the 14th falling edge, having being clocked out on the previous (13th) falling edge. In applications with a slower SCLK, it may be possible to read in data on each SCLK rising edge depending on the SCLK frequency. The first rising edge of SCLK after the $\overline{CS}$ falling edge would have the second leading zero provided, and the 13th rising SCLK edge would have DB0 provided.
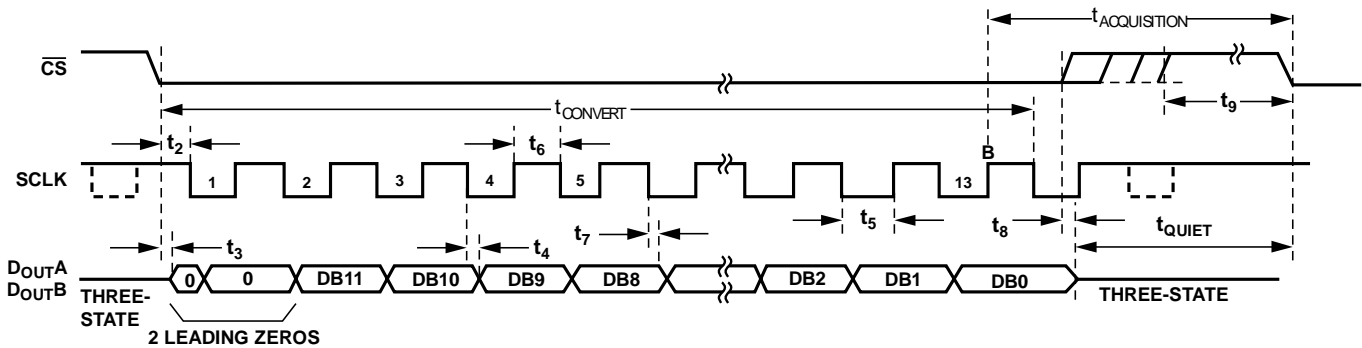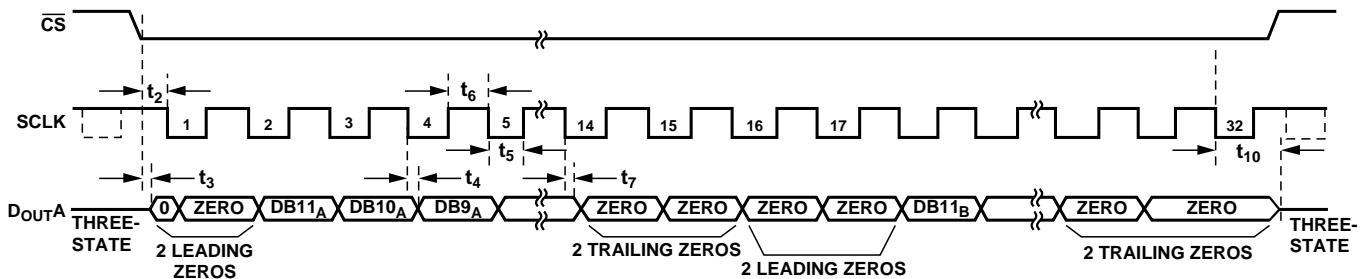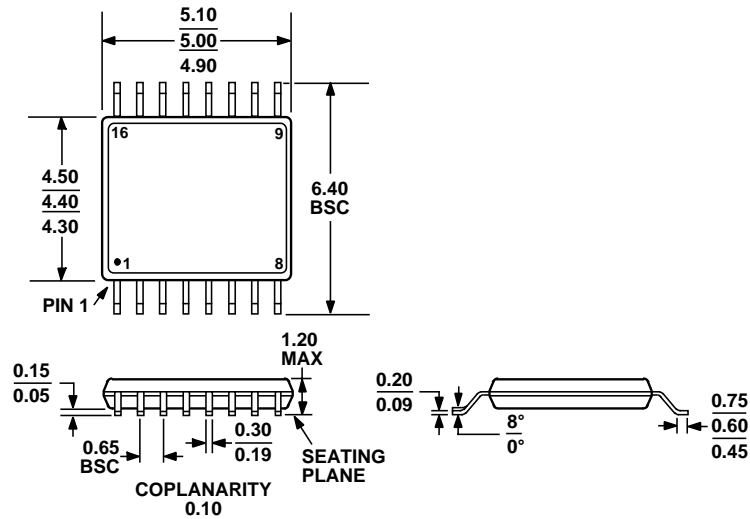

Figure 19. Serial Interface Timing Diagram

Figure 20. Reading Data from Both ADCs on One SDATA Line with 32 SCLKs

AD7352

OUTLINE DIMENSIONS

COMPLIANT TO JEDEC STANDARDS MO-153-AB

Figure 21. 16-LeadThin Shrink Small Outline Package
Dimensions shown in millimeters

ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option
AD7352BRUZ	−40°C to +85°C	16-Lead TSSOP	RU-16
AD7352BRUZ-REEL	−40°C to +85°C	16-Lead TSSOP	RU-16
AD7352BRUZ-REEL7	−40°C to +85°C	16-Lead TSSOP	RU-16
AD7352YRUZ	−40°C to +125°C	16-Lead TSSOP	RU-16
AD7352YRUZ-REEL	−40°C to +125°C	16-Lead TSSOP	RU-16
AD7352YRUZ-REEL7	−40°C to +125°C	16-Lead TSSOP	RU-16

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